

**Search Notes**

**Application/Control No.**

09/703,181

**Examiner**

Phallaka Kik

**Applicant(s)/Patent under Reexamination**

MOORE ET AL.

**Art Unit**

2825

**SEARCHED**

Class	Subclass	Date	Examiner
716	16,18,17	11/1/2004	PK
326	41,47,101	11/1/2004	PK
710	10	11/1/2004	PK
713	1,100	11/1/2004	PK
Above	updated	4/11/2005	PK
Above	updated	8/23/2005	PK
Above	search	8/23/2005	PK
370	366	8/23/2005	PK
709	221	8/23/2005	PK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
716	16,17,18	8/23/2005	PK
710	10	8/23/2005	PK
713	1,100	8/23/2005	PK
370/366; 709/221 -USPGPUB (see attached)		8/23/2005	PK

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS (EAST) USPAT, USPGPUB Clas/Sub searched: 716/1-18;326/38-45,47,63-81,101-103; 71-10;713/1-100 (see attached)	11/1/2004	PK
--EPO, JPO, IBM TDB, Derwent (see attached)	11/1/2004	PK
IEE/IEEE Xplore (see attached)	11/1/2004	PK
--USPAT, USPGPUB Updated searched: Class/Sub Searched: 716/1-18; 326/38-45,47,63-81,101-103; 71-10; 713/1-100 (see attached)	4/11/2005	PK
--USPAT, USPGPUB Updated searched: Class/Sub Searched: 716/1-18; 326/38-45,47,63-81,101-103; 71-10; 713/1-100 (see attached)	8/23/2005	PK
--USPAT, USPGPUB New search: 716/1-18; 326/38-45,47,63-81,101- 103; 71-10; 713/1-100; 370/all; 709/all (see attached)	8/23/2005	PK
--EPO, JPO, IBM TDB, Derwent New search (see attached)	8/23/2005	PK
--IEE/IEEE Xplore new search (see attached)	8/23/2005	PK